

High Speed, Simultaneous XRD-XRF Mapping of Geological Specimens with the Color X-ray Camera

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The Color X-ray Camera (CXC) [1] is a unique imaging spectrometer capable of recording both the position and energy of each X-ray event on the detector. This enables the simultaneous collection and analytical separation of both X-ray fluorescence and X-ray diffraction [2]. When combined with a micro focused X-ray source, the CXC can create X-ray maps of heterogeneous materials with mapping dwell times as low as 10 ms per point. In this relatively short measurement time, a full X-ray spectrum with an energy resolution of 145 eV at Mn $K\alpha$ is recorded along with a diffraction pattern with an angular range of approximately $150^\circ 2\theta$. Figure 1 shows the results from the analysis of a polished sample of Ocean Jasper. Geological specimens, particularly silica calcedonies like Ocean Jasper, pose a major challenge for ED-XRF mapping because of the presence of multiple crystalline phases and an abundance of so-called “Bragg Peaks”. In this experiment, a 100 μm X-ray beam (created by the XOS fleX-Beam system) was scanned over the sample with a dwell time of 2 s per point. The data recorded by the CXC contained significant diffraction, some of which overlapped with the Fe $K\alpha$ peak. Without correction, a user may falsely identify iron rich regions in the sample, but with correction, this problem can be eliminated.

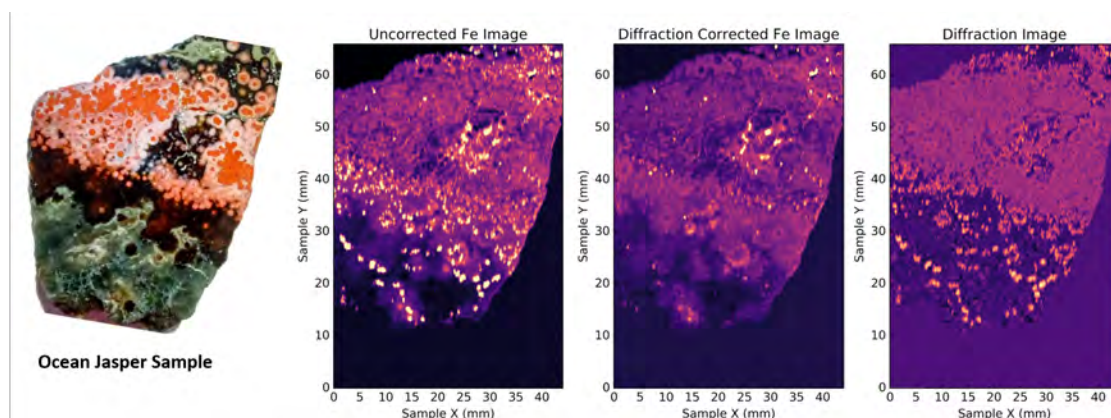


Figure 1: (Left) An optical image of a polished sample of Ocean Jasper. (Middle) The uncorrected Fe image, created by setting an energy window around the expected position of the Fe $K\alpha$ peak. (Right two images) When the diffraction from the sample is corrected, these bright spots disappear in the fluorescence image and are correctly associated with silica diffraction.

References:

- [1] Scharf, O., Ihle, S., Ordavo, I., *et al*, Compact pnCCD-based X-ray camera with high spatial and energy resolution: A color X-ray camera, *Analytical Chemistry*, **83** (2011), p. 2532:2538.
- [2] Leitenberger, W., Hartmann, R., Pietsch, U., *et al*, Application of a pnCCD in X-ray diffraction: a three-dimensional X-ray detector, *Journal of Synchrotron Radiation*, **15** (2008), p. 449:457.